Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/698,126	ACHARYA ET AL.	
Examiner	Art Unit	
Anish Sikri	2109	

SEARCHED				
Class	Subclass	Date	Examiner	
709	224	5/21/2007	AS	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	5/21/2007	AS		
Inventor name and Assignee search in PALM ExPO and EAST	5/21/2007	AS		
Consulted with Rafael Perez-Gutierrez and George Bugg	5/21/2007	AS		
(metric\$2 near3 (delay and loss and throughput and response and cost))	5/21/2007	AS		
(network near3 (delay and loss and throughput and response and cost))	5/21/2007	AS		
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